


<b>Search Notes</b>  	<b>Application/Control No.</b>  10663689	<b>Applicant(s)/Patent Under Reexamination</b>  LESTIDEAU, FABRICE
	<b>Examiner</b>  Chawan, Sheela C	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	103,118, 164, 224, 159, 190, 209, 116, 154, 254, 107, 171, 195,201,236,123	1/19/07	SCC
446	321,	"	"
704	246, 249,	"	"
150	103, 104	"	"
348	169,154,155	"	"
706	20,	"	"
383	106,	"	"
382	103,118,171,190	12/31/07	SCC
348	169	12/31/07	SCC
ABOVE SEARCH UP-DATE		12/31/07	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, US-PGPUB, USPAT,EPO,JPO,DERWENT,IBM-TDB.	1/19/07	SCC
INVENTOR NAME SEARCH.	"	"
382/103,118,171,190,116,107, 195,201,236,123.CCLS .	12/31/07	SCC
US-PATENT TEXT SEARCH ONLY.	12/31/07	SCC
348/169, 154,15.CCLS.	12/31/07	SCC
"5		
SEARCH EAST AND OTHER DATABASE , SEE THE ATTACHED SEARCH HISTORY.	12/31/07	SCC
SEARCH IEEE OR INSPEC DATA BASE.	12/31/07	SCC
SEARCH INTERFERENCE SEARCH .	12/31/07	SCC
ABOVE SEARCH UP-DATE.	12/31/07	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	103,118,171,190	12/31/07	SCC
348	169	12/31/07	SCC